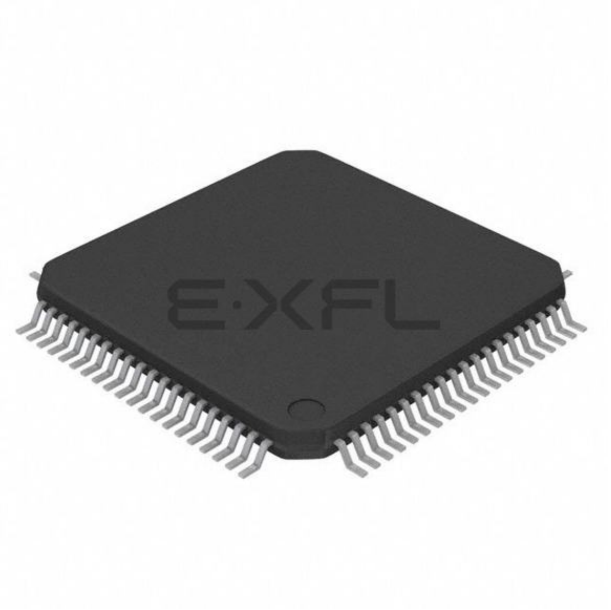
Microchip Technology - A40MX04-1VQ80I Datasheet



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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	80-TQFP
Supplier Device Package	80-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-1vq80i

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3 40MX and 42MX FPGAs

3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi’s patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • **Voltage Support of MX Devices**

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • **42MX IEEE 1149.1 Boundary Scan Circuitry**

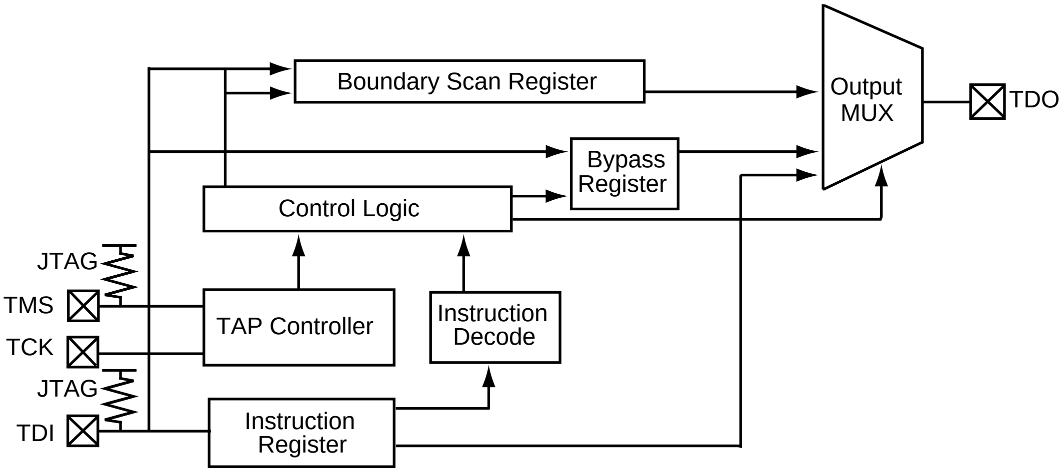

Table 9 • **Test Access Port Descriptions**

Port	**Description**
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • **Supported BST Public Instructions**

Instruction	**IR Code (IR2.IR0)**	**Instruction Type**	**Description**
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

Table 23 • **DC Specification (5.0 V PCI Signaling)[1]**

			PCI		MX		
Symbol	**Parameter**	**Condition**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
C_{IN}	Input Pin Capacitance			10	—	10	pF
C_{CLK}	CLK Pin Capacitance		5	12	—	10	pF
L_{PIN}	Pin Inductance			20	—	< 8 nH[4]	nH

1. PCI Local Bus Specification, Version 2.1, Section 4.2.1.1.
2. Maximum rating for VCCI –0.5 V to 7.0 V
3. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V.
4. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

Table 24 • **AC Specifications (5.0V PCI Signaling)***

			PCI		MX		
Symbol	**Parameter**	**Condition**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
ICL	Low Clamp Current	$-5 < VIN \leq -1$	–25 + (VIN +1) /0.015		–60	–10	mA
Slew (r)	Output Rise Slew Rate	0.4 V to 2.4 V load	1	5	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	2.4 V to 0.4 V load	1	5	2.8	4.3	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.1.2.

Table 34 • **A40MX02 Timing Characteristics (Nominal 5.0 V Operation) *(continued)***
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			0.7		0.8		0.9		1.1		1.5	ns
t_{INYL}	Pad-to-Y LOW			0.6		0.7		0.8		1.0		1.3	ns
Input Module Predicted Routing Delays[1]													
t_{IRD1}	FO = 1 Routing Delay			2.1		2.4		2.2		3.2		4.5	ns
t_{IRD2}	FO = 2 Routing Delay			2.6		3.0		3.4		4.0		5.6	ns
t_{IRD3}	FO = 3 Routing Delay			3.1		3.6		4.1		4.8		6.7	ns
t_{IRD4}	FO = 4 Routing Delay			3.6		4.2		4.8		5.6		7.8	ns
t_{IRD8}	FO = 8 Routing Delay			5.7		6.6		7.5		8.8		12.4	ns
Global Clock Network													
t_{CKH}	Input Low to HIGH	FO = 16		4.6		5.3		6.0		7.0		9.8	ns
		FO = 128		4.6		5.3		6.0		7.0		9.8	
t_{CKL}	Input High to LOW	FO = 16		4.8		5.6		6.3		7.4		10.4	ns
		FO = 128		4.8		5.6		6.3		7.4		10.4	
t_{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.1		3.6		5.1		
t_{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.01		3.6		5.1		
t_{CKSW}	Maximum Skew	FO = 16		0.4		0.5		0.5		0.6		0.8	ns
		FO = 128		0.5		0.6		0.7		0.8		1.2	
t_P	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0		ns
		FO = 128	4.8		5.6		6.3		7.5		10.4		
f_{MAX}	Maximum Frequency	FO = 16		188		175		160		139		83	MHz
		FO = 128		181		168		154		134		80	

Table 34 • **A40MX02 Timing Characteristics (Nominal 5.0 V Operation) *(continued)***
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		3.3		3.8		4.3		5.1		7.2	ns
t_{DHL}	Data-to-Pad LOW		4.0		4.6		5.2		6.1		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.3		4.9		5.8		8.0	ns
t_{ENZL}	Enable Pad Z to LOW		4.7		5.4		6.1		7.2		10.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.1	ns
t_{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d_{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF
CMOS Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.05		8.5	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3	ns
t_{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3	ns
t_{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.0	ns
t_{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d_{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07	ns/pF
d_{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35pF loading

Table 35 • **A40MX02 Timing Characteristics (Nominal 3.3 V Operation)**
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7	ns
t_{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0	ns
t_{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7	ns
Logic Module Predicted Routing Delays[1]												

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t_{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t_{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t_{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. *For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.*
4. *Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*
5. *Delays based on 35 pF loading.*

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.4		1.5		1.7		2.0		2.8	ns
t_{CO}	Sequential Clock-to-Q		1.4		1.6		1.8		2.1		3.0	ns
t_{GO}	Latch G-to-Q		1.4		1.5		1.7		2.0		2.8	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.6		1.7		2.0		2.3		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.6	ns
t_{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		2.5		2.8		3.2		3.7		5.2	ns
t_{DHL}	Data-to-Pad LOW		3.0		3.3		3.7		4.4		6.1	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.4		4.0		5.6	ns
t_{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.8		4.4		6.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.4		6.0		6.8		8.0		11.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.0		5.6		6.3		7.4		10.4	ns
t_{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t_{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.7		6.3		7.1		8.4		11.9	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

Table 43 • **A42MX24 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing^5 (continued)													
t_{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d_{TLH}	Capacitive Loading, LOW to HIGH			0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW			0.04		0.04		0.05		0.06		0.08	ns/pF
CMOS Output Module Timing^5													
t_{DLH}	Data-to-Pad HIGH			4.8		5.3		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW			3.5		3.9		4.1		4.9		6.8	ns
t_{ENZH}	Enable Pad Z to HIGH			3.6		4.0		4.5		5.3		7.4	ns
t_{ENZL}	Enable Pad Z to LOW			3.4		4.0		5.0		5.8		8.2	ns
t_{ENHZ}	Enable Pad HIGH to Z			7.2		8.0		9.0		10.7		14.9	ns
t_{ENLZ}	Enable Pad LOW to Z			6.7		7.5		8.5		9.9		13.9	ns
t_{GLH}	G-to-Pad HIGH			6.8		7.6		8.6		10.1		14.2	ns
t_{GHL}	G-to-Pad LOW			6.8		7.6		8.6		10.1		14.2	ns
t_{LSU}	I/O Latch Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d_{TLH}	Capacitive Loading, LOW to HIGH			0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW			0.04		0.04		0.05		0.06		0.08	ns/pF
t_{HEXT}	Input Latch External Hold	FO = 32	3.9		4.3		4.9		5.7		8.1		ns
		FO = 486	4.6		5.2		5.8		6.9		9.6		ns
t_P	Minimum Period ($1/f_{MAX}$)	FO = 32	7.8		8.7		9.5		10.8		18.2		ns
		FO = 486	8.6		9.5		10.4		11.9		19.9		ns

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • **A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

		–3 Speed		**–2 Speed**		**–1 Speed**		**Std Speed**		**–F Speed**		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t_{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t_{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t_{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t_{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t_{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t_{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Table 45 • **A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t_{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t_{GHL}	G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. *Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*
5. Delays based on 35 pF loading.

3.12 Pin Descriptions

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/ODiagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output

Figure 39 • **PL68**

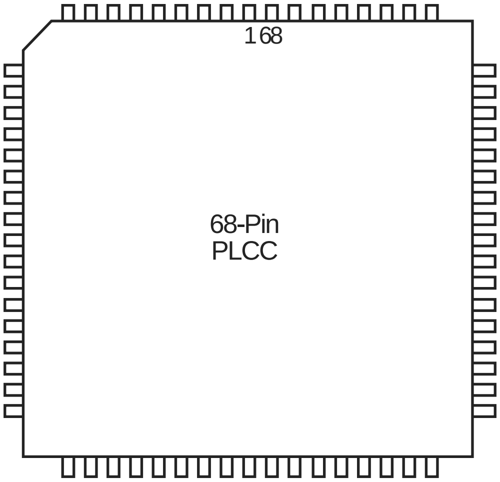

Table 48 • **PL68**

PL68		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
1	I/O	I/O
2	I/O	I/O
3	I/O	I/O
4	VCC	VCC
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	GND	GND
15	GND	GND
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	VCC	VCC
22	I/O	I/O
23	I/O	I/O

Table 48 • **PL68**

PL68		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCC	VCC
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	GND	GND
50	I/O	I/O
51	I/O	I/O
52	CLK, I/O	CLK, I/O
53	I/O	I/O
54	MODE	MODE
55	VCC	VCC
56	SDI, I/O	SDI, I/O
57	DCLK, I/O	DCLK, I/O
58	PRA, I/O	PRA, I/O
59	PRB, I/O	PRB, I/O
60	I/O	I/O

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Figure 44 • **PQ208**

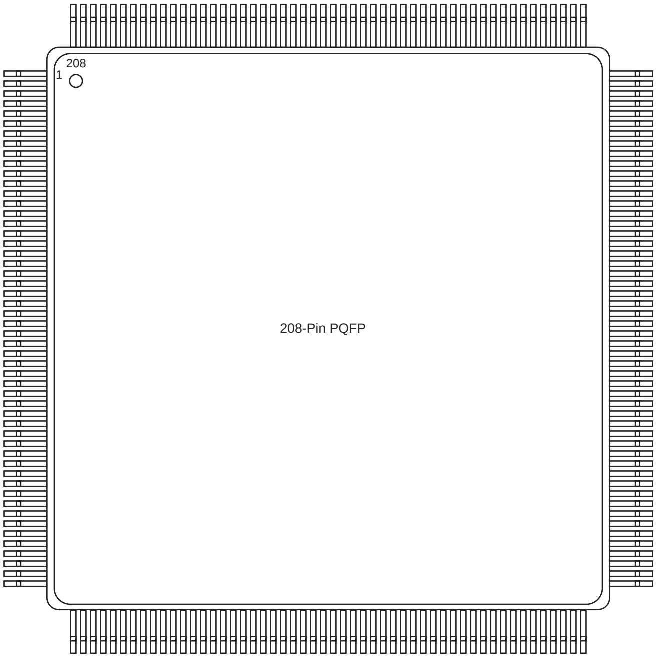

Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
1	GND	GND	GND
2	NC	VCCA	VCCA
3	MODE	MODE	MODE
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	NC	I/O	I/O
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	NC	I/O	I/O
17	VCCA	VCCA	VCCA
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O

Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

Figure 49 • **CQ208**

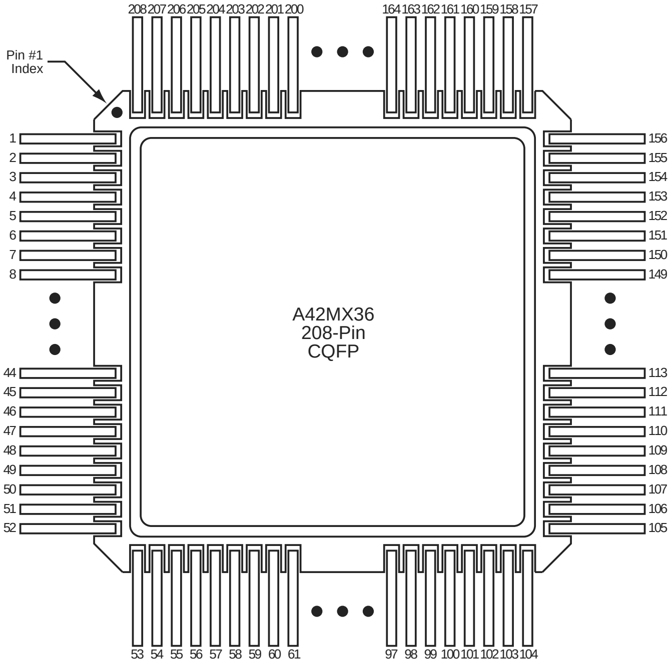

Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
B3	I/O
A2	I/O
C3	DCLK
B5	GNDA
E12	GNDA
J2	GNDA
M9	GNDA
B9	GNDI
C5	GNDI
E11	GNDI
F4	GNDI
J3	GNDI
J11	GNDI
L5	GNDI
L9	GNDI
C9	GNDQ
E3	GNDQ
K12	GNDQ
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI

Figure 53 • **CQ172**

Table 62 • **CQ172**

CQ172	
Pin Number	**A42MX16 Function**
1	MODE
2	I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	GND
8	I/O
9	I/O
10	I/O
11	I/O
12	VCC
13	I/O
14	I/O
15	I/O
16	I/O
17	GND
18	I/O
19	I/O
20	I/O

Table 62 • **CQ172**

60	I/O
61	I/O
62	I/O
63	I/O
64	I/O
65	GND
66	VCC
67	I/O
68	I/O
69	I/O
70	I/O
71	I/O
72	I/O
73	I/O
74	I/O
75	GND
76	I/O
77	I/O
78	I/O
79	I/O
80	VCCI
81	I/O
82	I/O
83	I/O
84	I/O
85	SDO
86	I/O
87	I/O
88	I/O
89	I/O
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	I/O
96	I/O
97	I/O
98	GND